Quad Latch

The MC10153 is a high speed, low power, MECL quad latch consisting of four bistable latch circuits with D type inputs and gated Q outputs. Open emitters allow a large number of outputs to be wire-ORed together. Latch outputs are gated, allowing direct wiring to a bus. When the clock is low, outputs will follow D inputs. Information is latched on positive going transition of the clock. The MC10153 provides the same logic function as the MC10133, except for inversion of the clock.

LOGIC DIAGRAM

Q0

Q1

Q2

Q0 2

Q1

6

V_{CC1} = PIN 1 V_{CC2} = PIN 16

V_{EE} = PIN 8

11 Q2

Q3

- $P_D = 310 \text{ mW typ/pkg}$ (No Load)
- $t_{pd} = 4.0$ ns typ

D0 3

G0

D1 7

CE

 $\mathbf{C}_{\mathbf{C}}$ 13

CE 12

D2 9

G1 10

D3 14

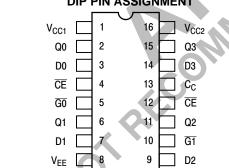
5

• t_r , $t_f = 2.0$ ns typ (20%-80%)

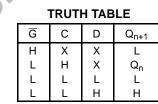


MARKING DIAGRAMS 16 ______ CDIP-16 MC10153L L SUFFIX AWLYYWW **CASE 620** 0000000 1 16 PDIP-16 MC10153P **P SUFFIX** AWLYYWW **CASE 648** angan PLCC-20 10153 **FN SUFFIX** AWLYYWW **CASE 775** = Assembly Location Α WL = Wafer Lot YY = Year

Q3 **DIP PIN ASSIGNMENT**



Pin assignment is for Dual-in-Line Package. For PLCC pin assignment, see the Pin Conversion Tables on page 18 of the ON Semiconductor MECL Data Book (DL122/D).



 $C = C_C + \overline{CE}$

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ORDERING INFORMATION

WW = Work Week

Device	Package	Shipping		
MC10153L	CDIP-16	25 Units / Rail		
MC10153P	PDIP-16	25 Units / Rail		
MC10153FN	PLCC-20	46 Units / Rail		

ELECTRICAL CHARACTERISTICS

					Test Limits					
		Pin Under	–30°C		+25°C			+85°C		
Characteristic	Symbol	Test	Min	Max	Min	Тур	Max	Min	Max	Unit
Power Supply Drain Current	Ι _Ε	8		83			75		83	mAdd
Input Current	l _{inH}	3 4 5 13		390 390 560 460			245 245 350 290		245 245 350 290	μAdc
	I _{inL}	3	0.5		0.5			0.3		μAdc
Output Voltage Logic 1	V _{OH}	2 2	-1.060 -1.060	-0.890 -0.890	-0.960 -0.960		-0.810 -0.810	-0.890 -0.890	-0.700 -0.700	Vdc
Output Voltage Logic 0	V _{OL}	2 2 2	-1.890 -1.890 -1.890	-1.675 -1.675 -1.675	-1.850 -1.850 -1.850		-1.650 -1.650 -1.650	-1.825 -1.825 -1.825	-1.615 -1.615 -1.615	Vdc
Threshold Voltage Logic 1	V _{OHA}	2 2 2 2 2 2 2 2 2 2 2 2 2	-1.080 -1.080 -1.080 -1.080 -1.080 -1.080 -1.080 -1.080		-0.980 -0.980 -0.980 -0.980 -0.980 -0.980 -0.980 -0.980			-0.910 -0.910 -0.910 -0.910 -0.910 -0.910 -0.910 -0.910	S	Vdc
Threshold Voltage Logic 0	V _{OLA}	2 2 2† 2‡ 2‡		-1.655 -1.655 -1.655 -1.655 -1.655 -1.655		8	-1.630 -1.630 -1.630 -1.630 -1.630 -1.630		-1.595 -1.595 -1.595 -1.595 -1.595 -1.595	Vdc
Switching Times (50 Ω Load)										ns
Propagation Delay	t ₃₊₂₊ t ₄₋₂₊ t ₅₋₂₊ t _{setup} t _{hold}	2 2 2 3 3	1.0 1.0 1.0 2.5 1.5	5.6 5.6 3.2	1.0 1.0 1.0 2.5 1.5	4.0 4.0 2.0 0.7 0.7	5.4 5.6 3.1	1.1 1.2 1.0 2.5 1.5	5.9 6.2 3.4	
Rise Time (20 to 80%)	t ₂₊	2	1.0	3.6	1.1	2.0	3.5	1.1	3.8	
Fall Time (20 to 80%)	t ₂₋	2	1.0	3.6	1.1	2.0	3.5	1.1	3.8	

† Output level to be measured after a clock pulse has been applied to the clock input (Pin 4)

‡ Data input at proper high/low level while clock pulse is high so that device latches ar proper high/low level for test. Levels are measured after device has latched. * Latch set to zero state before test.

VILmin

SENICE NO

ELECTRICAL CHARACTERISTICS (continued)

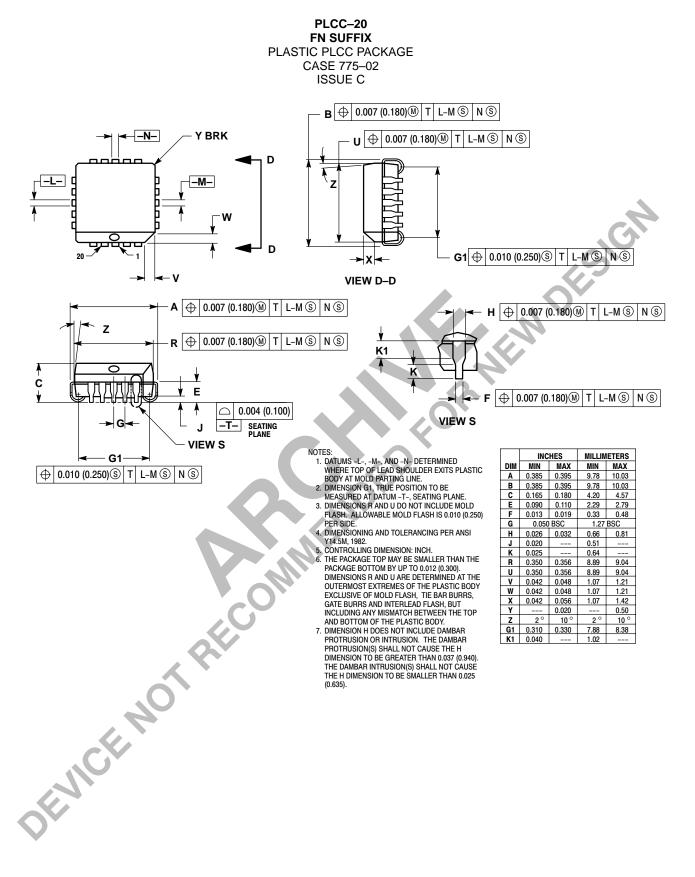
				TEST VOLTAGE VALUES (Volts)					
		@ Test Te	mperature	V _{IHmax}	V _{ILmin}	V _{IHAmin}	V _{ILAmax}	V _{EE}	
			–30°C	-0.890	-1.890	-1.205	-1.500	-5.2	
			+25°C	-0.810	-1.850	-1.105	-1.475	-5.2	
			+85°C	-0.700	-1.825	-1.035	-1.440	-5.2	
			Pin	TEST \	/OLTAGE A	PPLIED TO	PINS LISTED	BELOW	
Characteristic		Symbol	Under Test	V _{IHmax}	V _{ILmin}	V _{IHAmin}	V _{ILAmax}	V _{EE}	(V _{CC}) Gnd
Power Supply Drain Current		Ι _Ε	8		13			8	1, 16
Input Current		I _{inH}	3	3				8	1, 16
			4	4				8	1, 16
			5	5				8	1, 16
			13	13				8	1, 16
		I _{inL}	3		3			8	1, 16
Output Voltage L	ogic 1.	V _{OH}	2 2	3 3	4 13			8	1, 16 1, 16
Output Voltage L	.ogic 0	V _{OL}	2		3,13			8	1, 16
	.eg.e e	· OL	2	3,5	13			8	1, 16
			2		3,4			8	1, 16
Threshold Voltage L	ogic 1	V _{OHA}	2	3	4		5	8	1, 16
			2		4	3		8	1, 16
			2	3	4			8	1, 16
			2† 2‡	3				8 8	1, 16 1, 16
			2‡ 2‡					8	1, 16
			2	3			4	8	1, 16
			2	3			13	8	1, 16
Threshold Voltage L	ogic 0	V _{OLA}	2	3	4	5		8	1, 16
			2 2 2		4		3	8	1, 16
					4			8	1, 16
			2† 2‡	2				8 8	1, 16
			2‡ 2‡	3			13	8	1, 16 1, 16
Switching Times (50Ω	Load)			+1.11 V		Pulse In	Pulse Out	–3.2 V	+2.0 V
Propagation Delay		t ₃₊₂₊	2			3	2	8	1, 16
		t ₄₋₂₊	2	3*		4	2	8	1, 16
		t ₅₋₂₊	2			5	2	8	1, 16
		t _{setup}	3			3	2 2	8	1, 16
D T (- -)	0000	t _{hold})			3		8	1, 16
Rise Time (20 to	o 80%)	t ₂₊	2			3	2	8	1, 16
Fall Time (20 to			2			3	2	8	1, 16

‡ Data input at proper high/low level while clock pulse is high so that device latches ar proper high/low level for test. Levels are measured after device has latched.

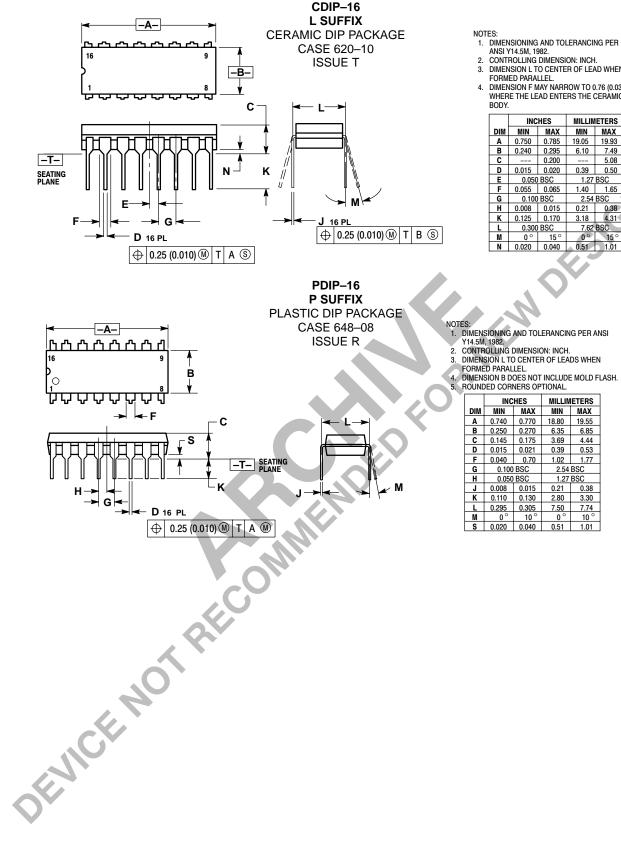
* Latch set to zero state before test.

Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50–ohm resistor to –2.0 volts. Test procedures are shown for only one gate. The other gates are tested in the same manner.

PACKAGE DIMENSIONS



PACKAGE DIMENSIONS



NOTES:

DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
CONTROLLING DIMENSION: INCH.
DIMENSION L TO CENTER OF LEAD WHEN FOOMED DRAWLES

DIMENSION LTO CENTER OF LEAD WHEN FORMED PARALLEL.
DIMENSION F MAY NARROW TO 0.76 (0.030) WHERE THE LEAD ENTERS THE CERAMIC BODY.

	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.750	0.785	19.05	19.93	
В	0.240	0.295	6.10	7.49	
С		0.200		5.08	
D	0.015	0.020	0.39	0.50	
Е	0.050 BSC		1.27 BSC		
F	0.055	0.065	1.40	1.65	
G	0.100 BSC		2.54 BSC		
Н	0.008	0.015	0.21	0.38	
Κ	0.125	0.170	3.18	4.31	
L	0.300 BSC		7.62	BSC	
Μ	0 °	15 °	0 °	15°	
Ν	0.020	0.040	0.51	1.01	

	INC	HES	MILLIN	ETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.740	0.770	18.80	19.55	
В	0.250	0.270	6.35	6.85	
С	0.145	0.175	3.69	4.44	
D	0.015	0.021	0.39	0.53	
F	0.040	0.70	1.02	1.77	
G	0.100 BSC		2.54 BSC		
Н	0.050	0.050 BSC		BSC	
J	0.008	0.015	0.21	0.38	
K	0.110	0.130	2.80	3.30	
L	0.295	0.305	7.50	7.74	
Μ	0°	10 °	0 °	10 °	
S	0.020	0.040	0.51	1.01	

Notes

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Notes

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